

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 246185US2S		SERIAL NO. <u>601726, 544</u> New Application	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Takeshi NAGAI, et al.			
				FILING DATE Herewith <u>12/4/03</u>		GROUP <u>2827</u>	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	AA	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
TN	AO	2002-133895	05/10/2002	JAPAN			X
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
TN	AW	Michael R. OUELLETTE, et al., "SHARED FUSE MACRO FOR MULTIPLE EMBEDDED MEMORY DEVICES WITH REDUNDANCY", IEEE 2001 Custom Integrated Circuits Conference, 2001, pgs. 191-194					
	AX						
	AY						
	AZ						
					<input type="checkbox"/> Additional References sheet(s) attached		
Examiner <u>/Tan Nguyen/</u>					Date Considered <u>11/21/2006</u>		
<small>*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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PATENT AND TRADEMARK OFFICE

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SERIAL NO.

10/726,544

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Takeshi NAGAI, et al.

FILING DATE

December 4, 2003

GROUP

2827

U.S. PATENT DOCUMENTS

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	AU					
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

TN	AW	T. C. MAY, et al., IEEE Transactions On Electron Devices, vol. ED-26, no. 1, pages 2-9, "ALPHA-PARTICLE-INDUCED SOFT ERRORS IN DYNAMIC MEMORIES", January 1979
TN	AX	J.F. Ziegler, et al., IEEE Journal of Solid-State Circuits, vol. 33, no. 2, pages 246-252, "COSMIC RAY SOFT ERROR RATES OF 16-MB DRAM MEMORY CHIPS", February 1998
	AY	
	AZ	

☐ Additional References sheet(s) attached

Examiner

/Tan Nguyen/

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SHEET 1 OF 1

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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
TN	AO	2001-358313	12/26/2001	Japan		X
TN	AP	2003-233999	8/22/2003	Japan		X
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